Search Note	Application/Control No.	Applicant(s)/Pat Reexamination	Applicant(s)/Patent Under Reexamination	
	Examiner	Art Unit		
,	SEARCHED	I.		
Class	Subclass	Date	Examiner	
	SEARCH NOTE	 ≣S	· · · · · · · · · · · · · · · · · · ·	
Search Notes		Date	Examiner	
	INTERFERENCE SE	:ARCH		
	Subclass	Date	Examiner	

U.S. Patent and Trademark Office Part of Paper No. :